

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
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10603407_CLS.txt

10603407, CCS, CTX
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10603407 on November 18, 2004

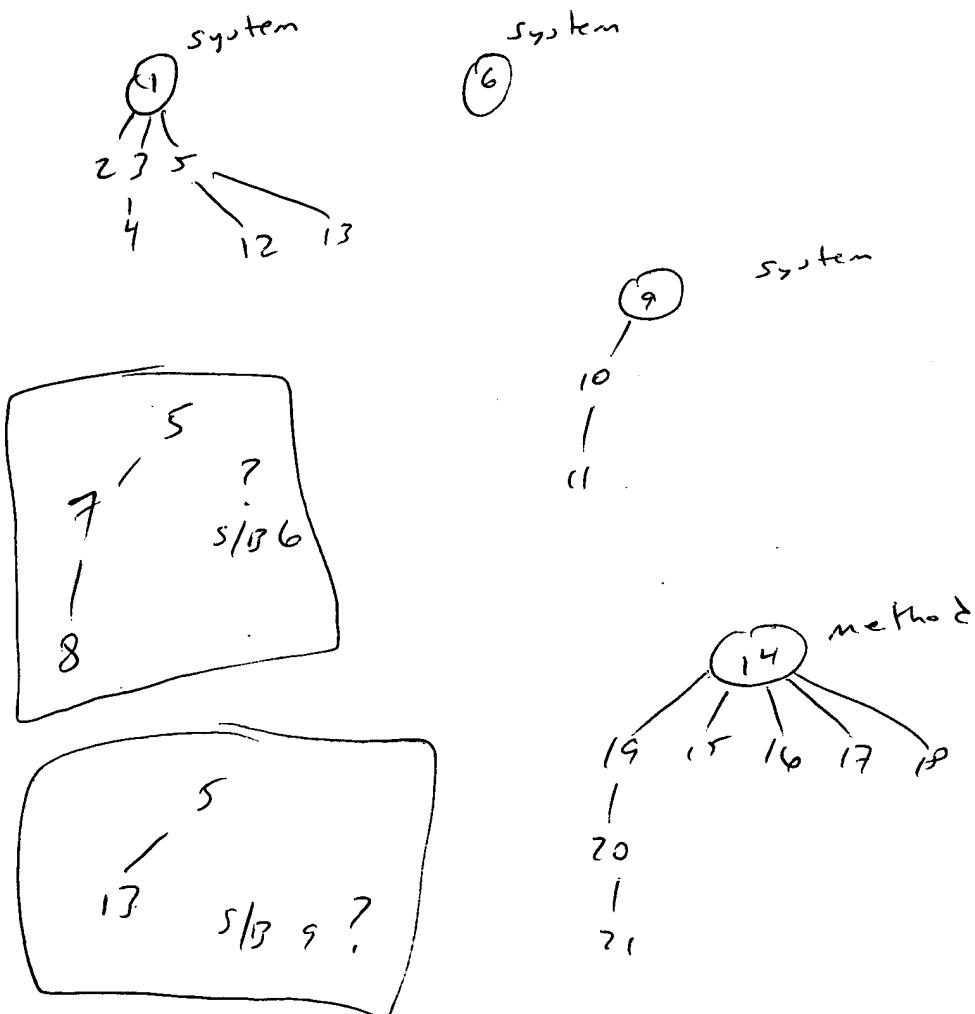
original classifications

10 714/727
3 324/158.1
3 705/400
2 324/537
2 714/726
2 714/738

MP EP 2173.05(s)

Cross-Reference classifications

6 714/734
4 324/73.1
4 714/726
4 714/733
3 222/638
3 222/639
3 324/754
3 377/15
3 714/724
2 257/E25.023
2 324/158.1
2 324/763
2 361/684
2 361/783
2 377/16
2 714/30
2 714/720
2 714/731



JTA6 Tech. - international standard

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10603407_CLSTITLES.txt
Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10603407 on November 18, 2004

10 714/727 (10 OR, 0 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))
714/727 ...Boundary scan

7 714/734 (1 OR, 6 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/734 ..Structural (in-circuit test)

6 714/726 (2 OR, 4 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))

5 324/158.1 (3 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/158.1 MISCELLANEOUS

5 324/73.1 (1 OR, 4 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

5 714/733 (1 OR, 4 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/733 ..Built-in testing circuit (BILBO)

4 324/754 (1 OR, 3 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .of individual circuit component or element
324/754 ..with probe elements

4 714/724 (1 OR, 3 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing

3 222/638 (0 OR, 3 XR)
Class 222 : DISPENSING
222/638 .INCLUDING TIMER

3 222/639 (0 OR, 3 XR)
Class 222 : DISPENSING
222/638 INCLUDING TIMER

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222/639 .For timing dispensing period

3 324/537 (2 OR, 1 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .of individual circuit component or element

3 377/15 (0 OR, 3 XR)
Class 377 : ELECTRICAL PULSE COUNTERS, PULSE DIVIDERS, OR
SHIFT REGISTERS: CIRCUITS AND SYSTEMS
377/1 APPLICATIONS
377/15 .Counting based on number of times machine or
apparatus operates

3 705/400 (3 OR, 0 XR)
Class 705 : DATA PROCESSING: FINANCIAL, BUSINESS
PRACTICE, MANAGEMENT, OR COST/PRICE DETERMINATION
705/400 FOR COST/PRICE

3 714/731 (1 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/726 ..Scan path testing (e.g., level sensitive scan
design (LSSD))
714/731 ...Clock or synchronization

3 714/738 (2 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY
714/699 PULSE OR DATA ERROR HANDLING
714/724 .Digital logic testing
714/738 ..Including test pattern generator

2 257/E25.023 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/E25.001 ASSEMBLIES CONSISTING OF PLURALITY OF
INDIVIDUAL SEMICONDUCTOR OR OTHER SOLID-STATE DEVICES
(EPO)
circuit
257/E25.002 .All devices being of same type, e.g.,
assemblies of rectifier diodes (EPO)
257/E25.022 ..Devices having separate containers (EPO)
257/E25.023 ...Device consisting of plurality of
semiconductor or other solid-state devices or components
formed in or on common substrate, e.g., integrated
device (EPO)

2 324/755 (1 OR, 1 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS
324/537 .of individual circuit component or element
324/754 ..With probe elements
324/755 ...Internal of or on support for device under
test (DUT)

2 324/763 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF

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ELECTRIC COMPONENTS

324/537 .of individual circuit component or element
324/763 ..DUT including test circuit

2 361/684 (0 OR, 2 XR)
Class 361 : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES

361/600 HOUSING OR MOUNTING ASSEMBLIES WITH DIVERSE
ELECTRICAL COMPONENTS
361/679 .For electronic systems and devices
361/683 ..Computer related support
361/684 ...Memory unit support

2 361/783 (0 OR, 2 XR)
Class 361 : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES

361/600 HOUSING OR MOUNTING ASSEMBLIES WITH DIVERSE
ELECTRICAL COMPONENTS
361/679 .For electronic systems and devices
361/748 ..Printed circuit board
361/760 ...Connection of components to board
361/783Having semiconductive device

2 377/16 (0 OR, 2 XR)
Class 377 : ELECTRICAL PULSE COUNTERS, PULSE DIVIDERS, OR
SHIFT REGISTERS: CIRCUITS AND SYSTEMS

377/1 APPLICATIONS
377/16 .Determining machine or apparatus operating
time or monitoring machine, apparatus or operation

2 714/30 (0 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
714/1 .Reliability and availability
714/25 ..Fault locating (i.e., diagnosis or testing)
714/27 ...Particular access structure
714/30Built-in hardware for diagnosing or testing
within-system component (e.g., microprocessor test mode
circuit, scan path)

2 714/719 (1 OR, 1 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING
714/718 .Memory testing
714/719 ..Read-in with read-out and compare

2 714/720 (0 OR, 2 XR)
Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING
714/718 .Memory testing
714/719 ..Read-in with read-out and compare
714/720 ...Special test pattern (e.g., checkerboard,
walking ones)

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4800301 67
5268645 61
5777932 59
6092226 59
5964894 56
4822295 54
4573008 54
6049740 54
4342959 54
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PLUS Search Results for S/N 10603407, Searched November 18, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

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